

Search Notes

Application/Control No.

10/528,529

Examiner

Nam Huynh

Applicant(s)/Patent under
Reexamination

VANDER VEEN ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	415	5/7/2007	NTH
	566		
379	142.02	5/7/07	NTH
	142.06		
	142.17		
	207.15		
	433.04		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See	Above	5/7/2007	NTH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	5/7/2007	NTH
Consulted with George Eng in regards to allowable subject matter.	5/7/2007	NTH
Interference search conducted.	5/7/2007	NTH